NanoParticle Collection Device for Ultra-Pure Water

New Analytical tool for Rapid Identification of Sub-50 Nanometer Elemental Contamination

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ITRS Committee

Participating Fabs

Balazs NanoAnalysis

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Existing Particle Metrology Limits Front End Process Defect Reduction

"The UPW section of Table YE9 highlights the inability of particle metrology in UPW to support the targets established by the Front End Process defect targets. Further work is needed to understand particle deposition from UPW and to speciate organics in UPW."

—ITRS 2008 Update

System is Designed to Address ITRS Particle Metrology Needs by:

Capturing Particles in UPW

Retaining and Agglomerating Particles

 Releasing Particles to SEM Membranes for Analysis

Operation is Based on Fundamental Physics

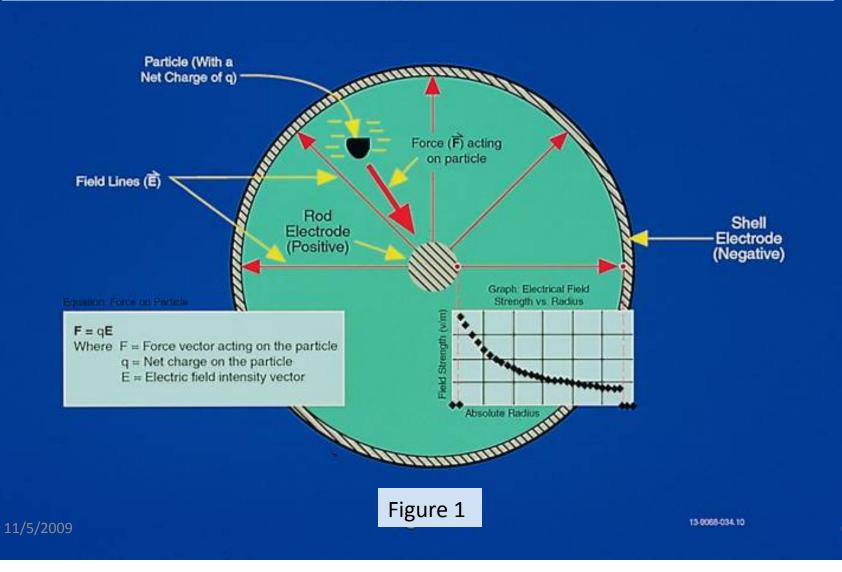
 Ultra-Pure Water is relatively non-conductive so we can establish an electric field in it

 Majority of particles in ultra-pure water have electrical charge

 Using proper electrical and hydraulic design, it removes particles from ultra-pure water

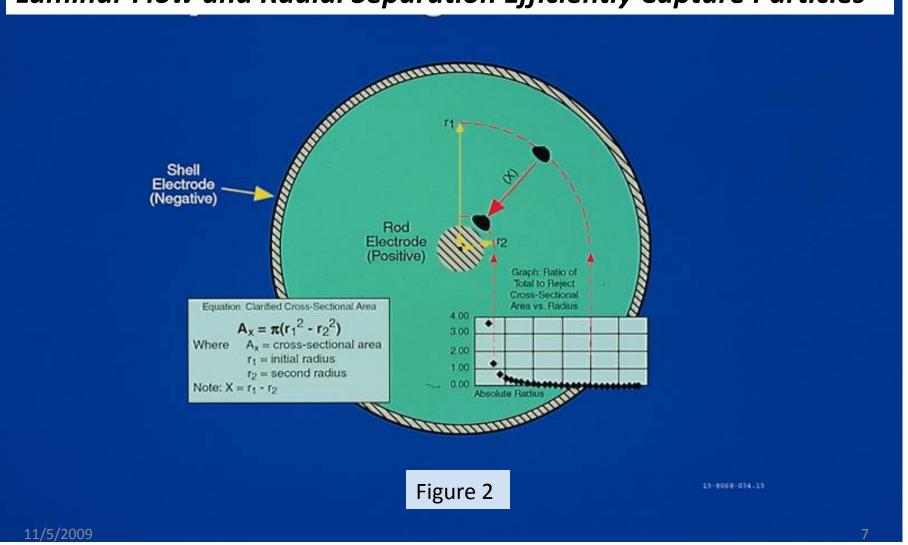
Electrical Design of the Chamber

Electromagnetic Field moves charged particles through UPW

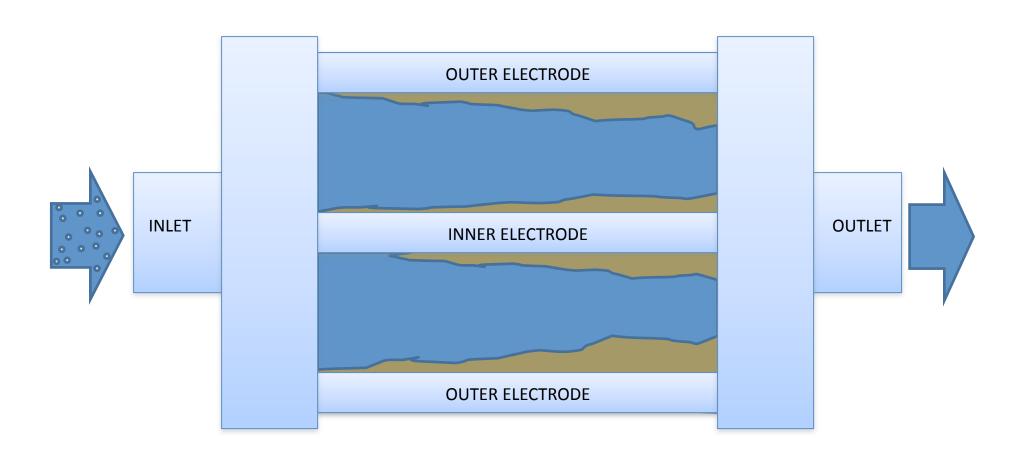


Hydraulic Design of the Chamber

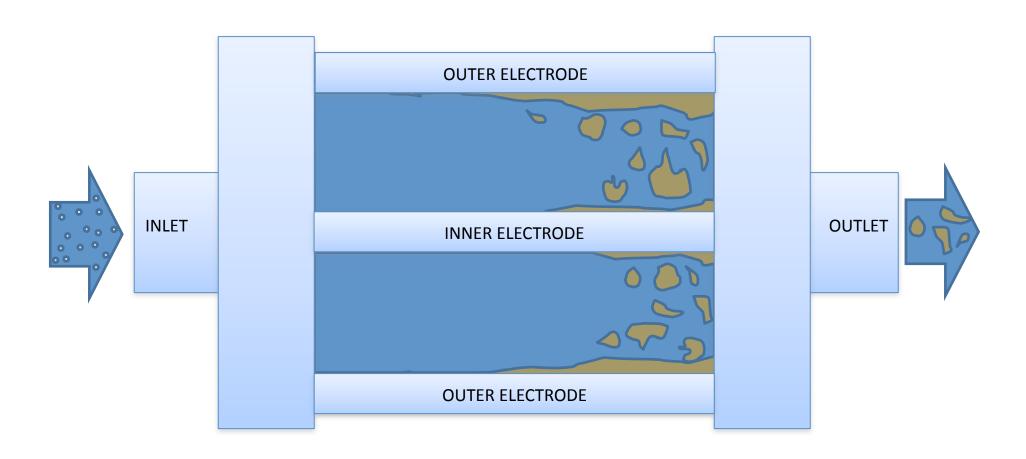




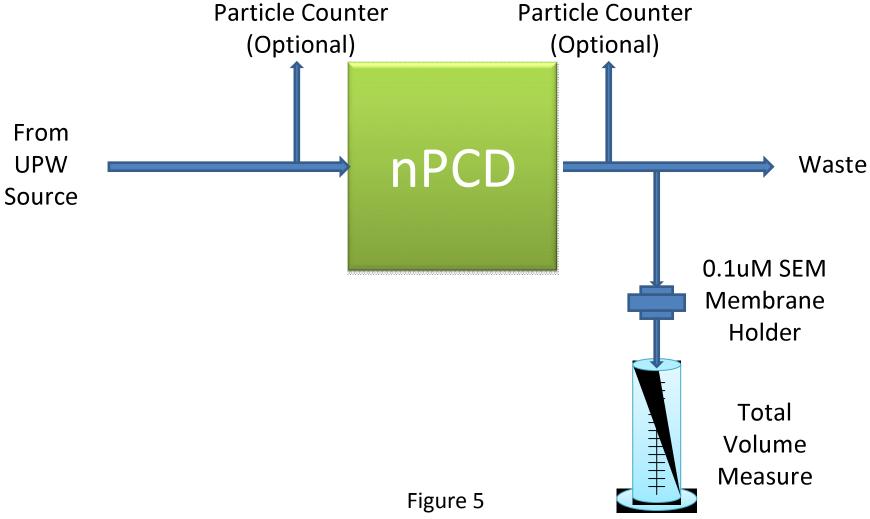
The Chamber Captures and Agglomerates Contamination on Electrodes



Release mode drives agglomerated contaminants back off the electrodes.

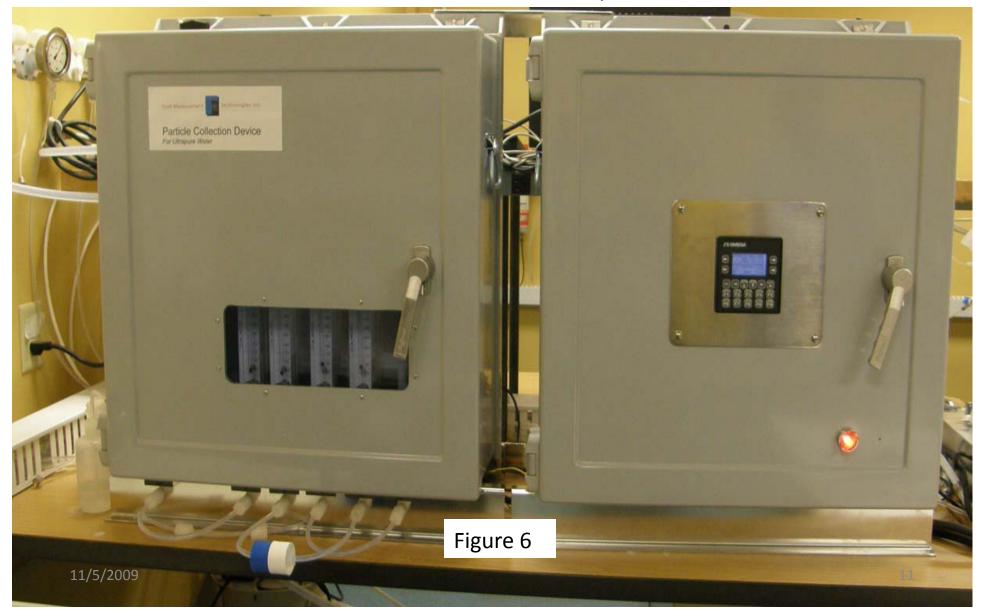


Traditional 0.1 Micron Sample Membranes Collect Concentrated Contamination for SEM/EDS Analysis



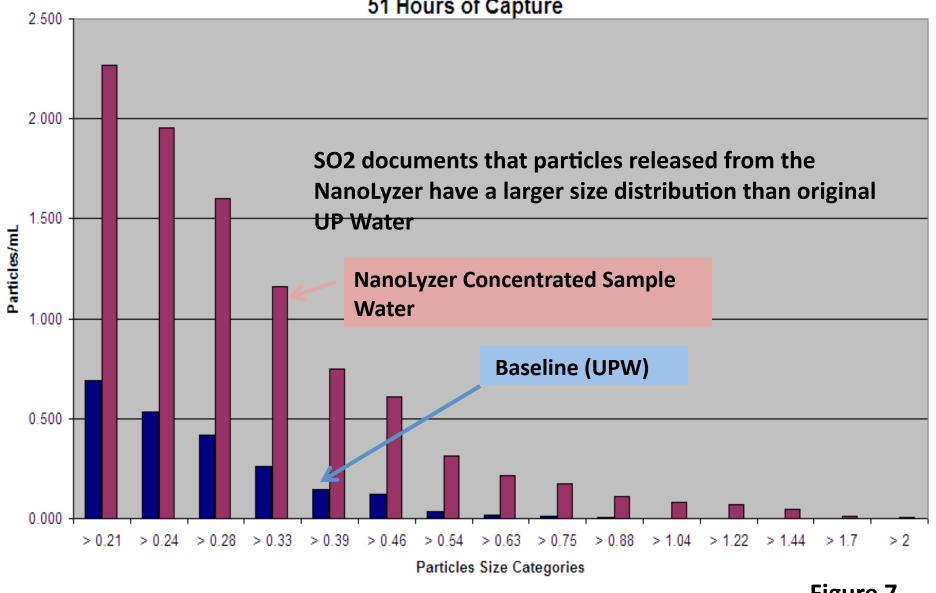
NanoLyzer is Built for UPW Service

Separate Boxes Contain Wetted and Electrical Systems Wetted Materials Include PFA, PVDF, and Electropolished 316L Stainless Steel



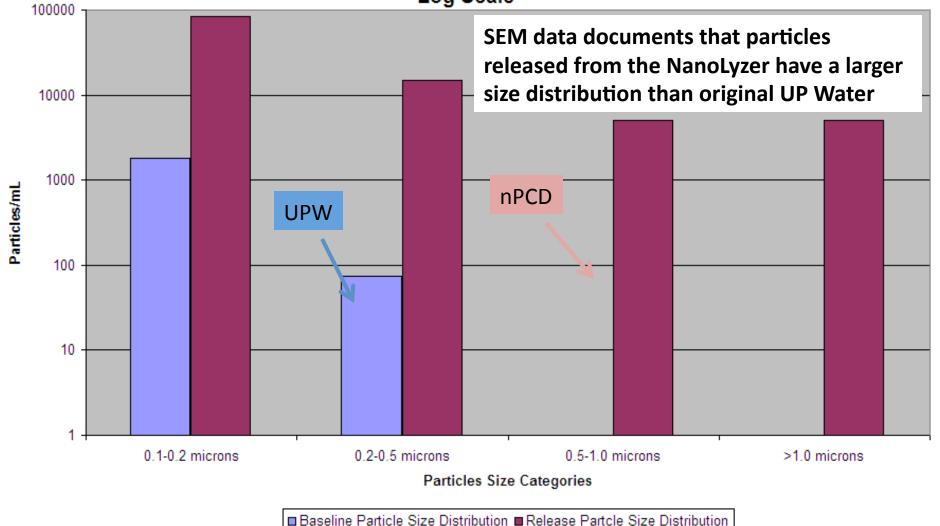
n PCD Aggomerates Sub-50 Nanometer Particles

PMS SO2 Laser Particle Counter 51 Hours of Capture

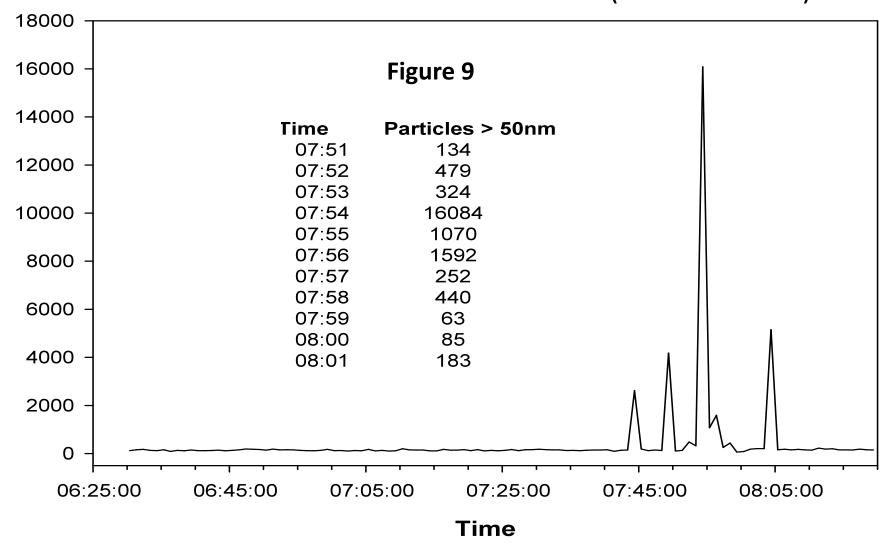


n PCD Aggomerates Sub-50 Nanometer Particles

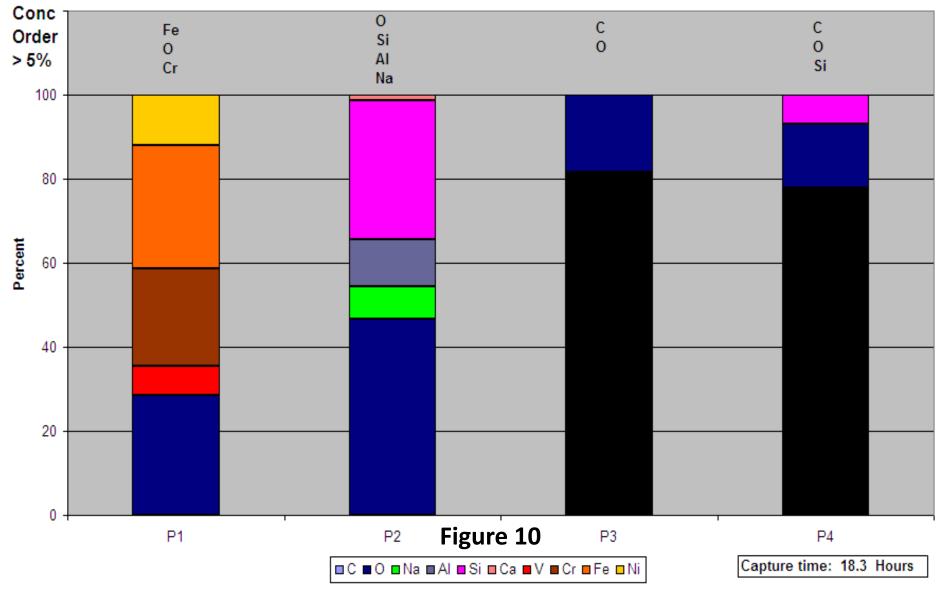
SEM Membrane Particle Data Capture Time of 44.3 Hours Log Scale



Laser Particle Counter Documented Agglomerated Particles Were Released during ITRS Round Robin Testing All Particles Greater than 50 Nanometers (Nanocount 50)



NanoLyzer Identified Elemental Composition of UPW Particles during ITRS Round Robin Percent Elemental Concentration in Particles



NanoLyzer Testing Identified a Large Variety of Elements in UPW

- Carbon
- Nitrogen
- Oxygen
- Fluorine
- Sodium
- Magnesium
- Aluminum

- Silica
- Phosphorus
- Sulfur
- Chloride
- Potassium
- Calcium
- Titanium

- Vanadium
- Chromium
- Iron
- Nickel
- Zinc
- Bromine
- Antimony

NanoLyzer Testing Identified the Most Common Nano-Contaminants in UPW

Carbon/Oxygen

Silica /Oxygen/Aluminum

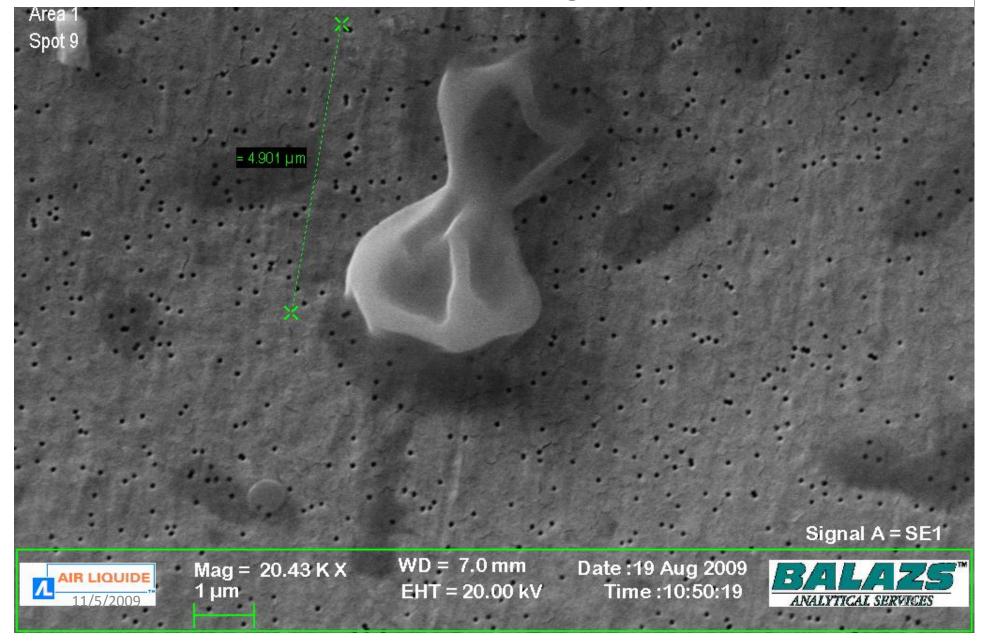
Iron/Chromium/Nickel/Oxygen

Fluorine/Carbon/Oxygen

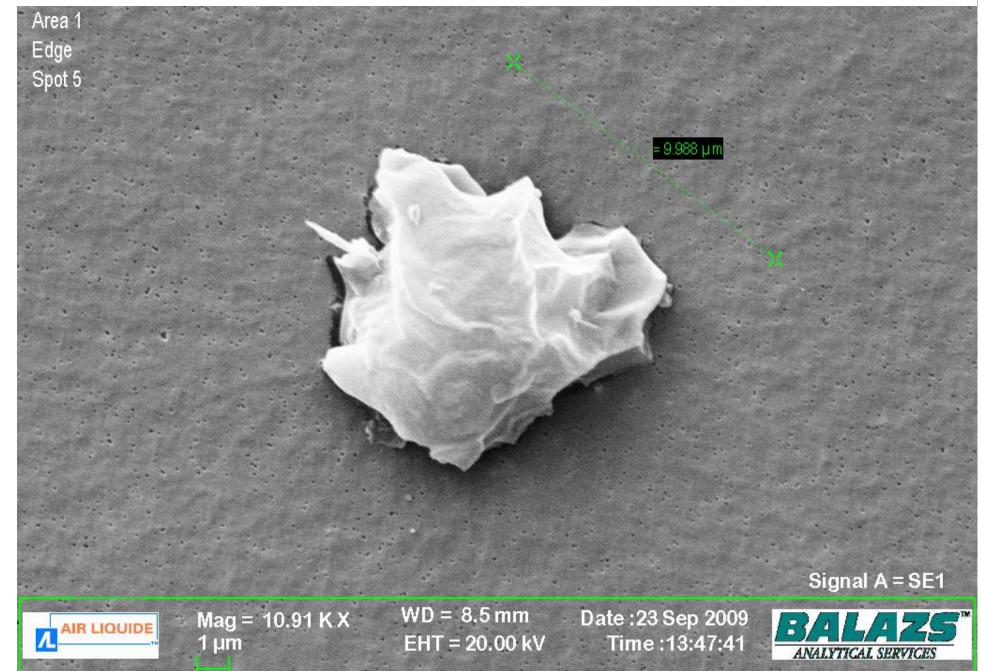
NanoLyzer Collects Particles for Visual and Elemental Analysis Carbon Particle – Bacterial Shape



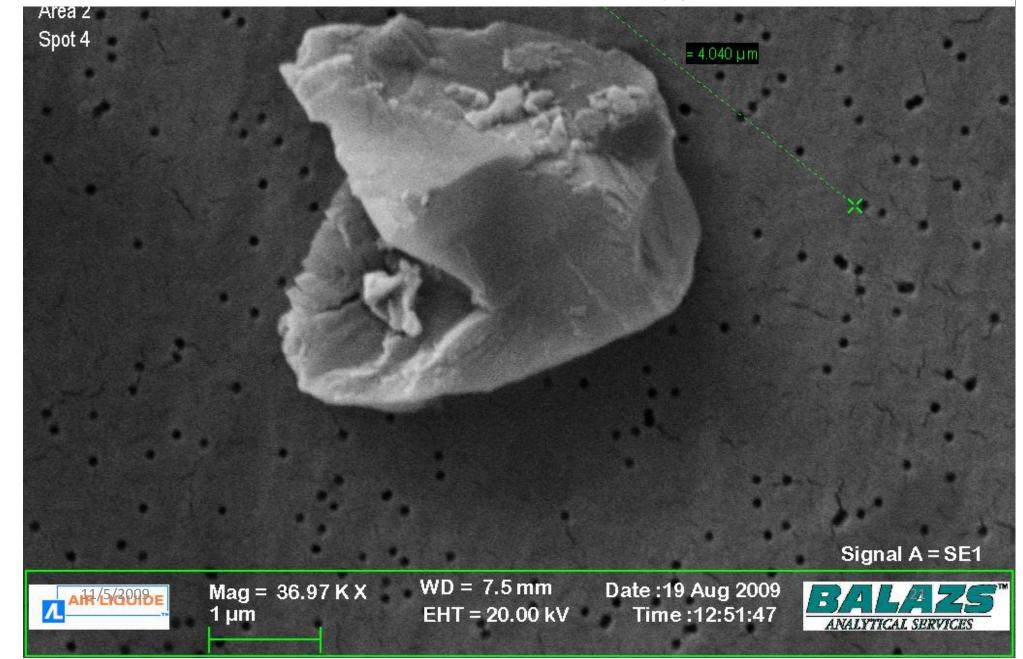
NanoLyzer Collects Particles for Visual and Elemental Analysis Carbon Particle – Biological Material



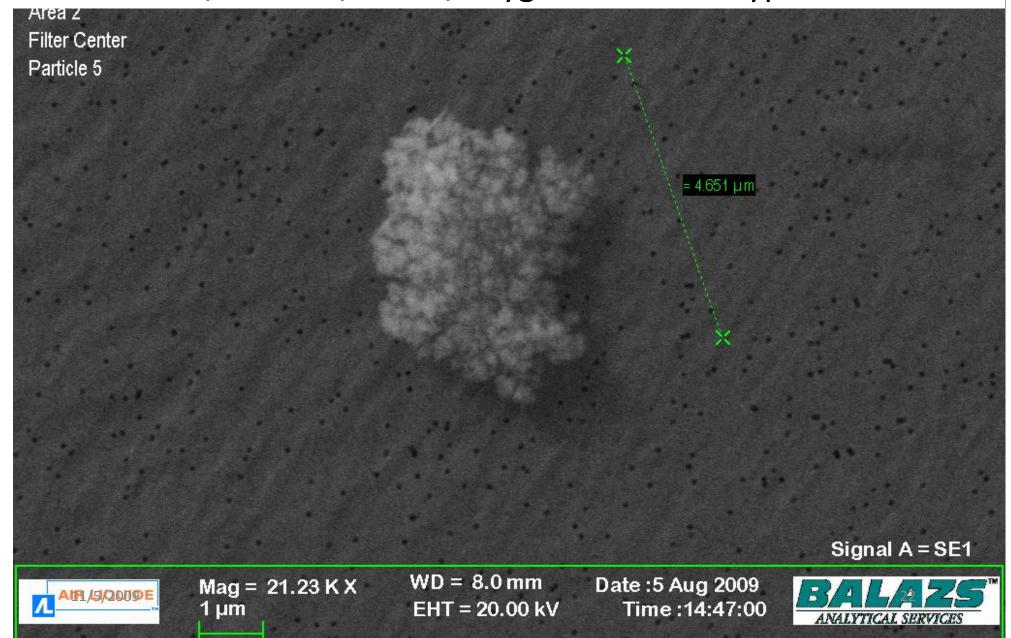
NanoLyzer Collects Particles for Visual and Elemental Analysis Silica/Oxygen Particle



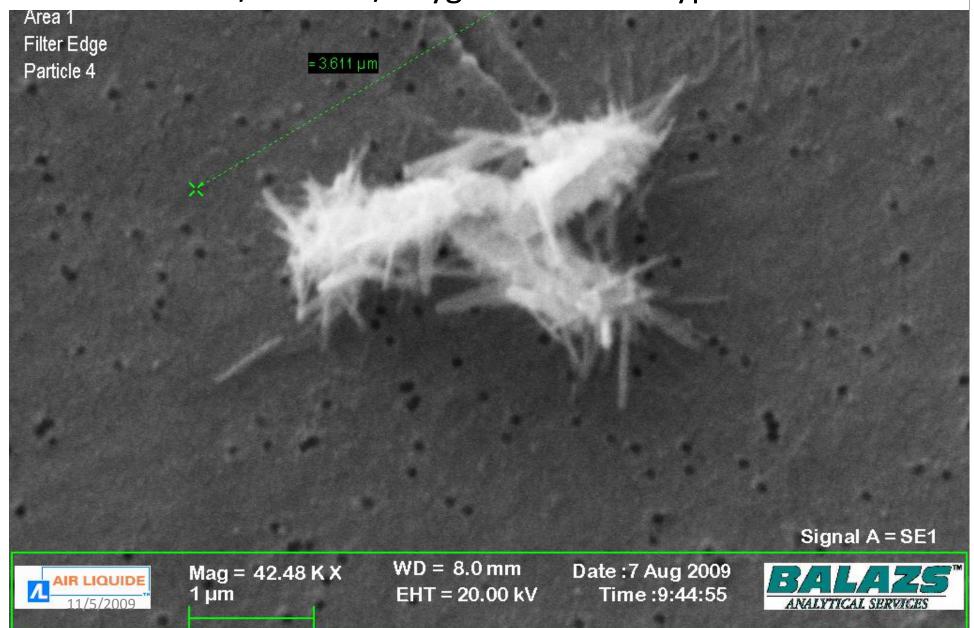
NanoLyzer Collects Particles for Visual and Elemental Analysis Silica/Aluminum/Potassium/Oxygen Particle



NanoLyzer Collects Particles for Visual and Elemental Analysis Iron/Chrome/Nickel/Oxygen Particle – Type One



NanoLyzer Collects Particles for Visual and Elemental Analysis Iron/Chrome/Oxygen Particle – Type Two



NanoLyzer Collects Particles for Visual and Elemental Analysis Fluorine/Carbon/Oxygen Particle



The NanoLyzer Is a New Analytical Tool That Rapidly Identifies Sub-50 nm Elemental Contamination.

- Captures and Agglomerates Particles below 50 nm
- Enables visible and elemental identification of contamination
- Leverages and enhances proven SEM/EDS analysis
- Supports particle concentration and mass data calculation
- Provides fast and actionable data
- Standardizes data between process points and facilities

NanoLyzer Supports the ITRS 2008 Front End Process Particle Metrology Needs for Ultrapure Water Process Control and Front End Defect Reduction

The next paper will provide specific elemental contaminant identification from five ITRS member fabs.